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UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: YAMAGISHI, Yasuo, et al.

Group Art Unit: 2829

Serial No.: 10/621,445

Examiner: Jermele M. HOLLINGTON

Filed: July 18, 2003

P.T.O. Confirmation No.: 1112

For: PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREOF

AMENDMENT UNDER 37 CFR §1.116

- EXPEDITED RESPONSE -
GROUP ART UNIT 2829

MAIL STOP AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 5, 2006

Sir:

In response to the Final Office Action dated April 18, 2006, please amend the above-

identified application as follows:

Please
enter
in H
6/13/06